## Notice of References Cited Application/Control No. O9/435,315 Examiner JOHN J. LEE Applicant(s)/Patent Under Reexamination MARKO ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,091,932	07-2000	Langlais, Brian	725/111
*	В	US-6,154,452	11-2000	Marko et al.	455/13.1
*	С	US-6,424,817	07-2002	Hadden et al.	455/3.02
*	D	US-6,816,704	11-2004	Fukuda, Kunio	455/7
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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